Acc.V Spot Magn Det WD Exp |-

10.0 kV 3.0 55988x TLD 5.0 1 VHF#18-Recipe#4-2x300s



3.56 µm

1 μm

Figure 14 (a), (b), and (c): Dry etch profile of SiO₂ using VHF tool and **Recipe#4 with 2X300 s** (2 cycles and 300 s for each cycle).

Undercut etch rate=3.5μm/10min=3500 Å/min



Figure 15 (a), (b), and (c): Dry etch profile of SiO₂ using VHF tool and **Recipe#4 with 4X300 s** (4 cycles and 300 s for each cycle).



Average opening width (including the undercuts) = 25.7 μ m

Average Undercut= (25.7-12.1)/2=6.8μm

Undercut etch rate=6.8µm/20min=3400 Å/min



Figure 16 (a), (b), and (c): Dry etch profile of SiO₂ using VHF tool and **Recipe#4 with 6X300 s** (6 cycles and 300 s for each cycle).



Average opening width (including the undercuts) = $32.1 \ \mu m$

Average Undercut= (32.1-12.1)/2=10μm

Undercut etch rate=10μm/30min=3330 Å/min

Figure 17 SiO₂ undercut vs. etch time using Recipe#4.





Figure 18 (a), (b), and (c): Dry etch profile of SiO₂ using VHF tool and **Recipe#5 with 2X300 s** (2 cycles and 300 s for each cycle).



Figure 19 (a), (b), and (c): Dry etch profile of SiO₂ using VHF tool and **Recipe#5 with 4X300 s** (4 cycles and 300 s for each cycle).



Figure 20 (a), (b), and (c): Dry etch profile of SiO₂ using VHF tool and **Recipe#5 with 6X300 s** (6 cycles and 300 s for each cycle).



Average opening width (including the undercuts) = 32.9 μ m

Average Undercut= (32.9-12.1)/2≈10.4μm

Undercut etch rate=10.4μm/30min=3470 Å/min Figure 21 SiO₂ undercut vs. etch time using Recipe#5.



SiO₂ Undercut vs. Etch Time (Recipe#5)

Recipe#	HF Partial Pressure (T)	EtOH Partial Pressure (T)	SiO₂ Undercut Etch Rate (Å/min)
1	13.0	14.4	177
2	20.3	22.9	1100
3	34.1	26.0	2390
4	39.3	26.2	3410
5	46.8	21.1	3680

Table 2 Vapor HF partial pressure and EtOH partial pressure vs SiO₂ undercut etch rate.

Figure 22 SiO₂ undercut etch rate vs vapor HF partial pressure.



Figure 23 SiO₂ undercut etch rate vs vapor EtOH partial pressure.

